

# STP3NB60 STP3NB60FP

N-CHANNEL 600V - 3.3 Ω - 3.3A TO-220/TO-220FP PowerMESH™ MOSFET

**Table 1. General Features** 

Туре	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
STP3NB60	600 V	< 3.6 Ω	3.3 A
STP3NB60FP	600 V	< 3.6 Ω	2.2 A

#### **FEATURES SUMMARY**

- TYPICAL  $R_{DS(on)} = 3.3 \Omega$
- EXTREMELY HIGH dv/dt CAPABILITY
- 100% AVALANCHE TESTED
- VERY LOW INTRINSIC CAPACITANCES
- GATE CHARGE MINIMIZED

#### **DESCRIPTION**

Using the latest high voltage MESH OVERLAY™ process, STMicroelectronics has designed an advanced family of power MOSFETs with outstanding performances. The new patent pending strip layout coupled with the Company's proprietary edge termination structure, gives the lowest RDS(on) per area, exceptional avalanche and dv/dt capabilities and unrivalled gate charge and switching characteristics.

#### **APPLICATIONS**

- HIGH CURRENT, HIGH SPEED SWITCHING
- SWITCH MODE POWER SUPPLIES (SMPS)
- DC-AC CONVERTERS FOR WELDING EQUIPMENT AND UNINTERRUPTIBLE POWER SUPPLIES AND MOTOR DRIVE

Figure 1. Package

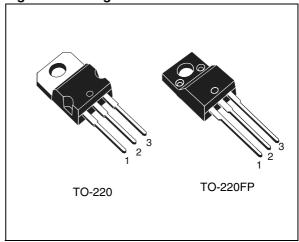
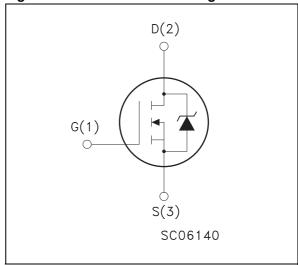


Figure 2. Internal Schematic Diagram



**Table 2. Order Codes** 

Part Number Marking		Package	Packaging
STP3NB60	P3NB60	TO-220	TUBE
STP3NB60FP	P3NB60FP	TO-220FP	TUBE

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# STP3NB60/FP

**Table 3. Absolute Maximum Ratings** 

Symbol	Parameter	Va	lue	Unit
Symbol	Farameter	STP3NB60	STP3NB60FP	Onit
V <sub>DS</sub>	Drain-source Voltage (V <sub>GS</sub> = 0)	6	00	V
V <sub>DGR</sub>	Drain- gate Voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	6	00	V
V <sub>GS</sub>	Gate-source Voltage	±	30	V
I <sub>D</sub>	Drain Current (cont.) at T <sub>C</sub> = 25 °C	3.3	2.2	А
I <sub>D</sub>	Drain Current (cont.) at T <sub>C</sub> = 100 °C	2.1	1.4	Α
I <sub>DM</sub> <sup>(1)</sup>	Drain Current (pulsed)	13.2	13.2	Α
P <sub>tot</sub>	Total Dissipation at T <sub>C</sub> = 25 °C	80	35	W
	Derating Factor	0.64	0.28	W°/C
dv/dt (2)	Peak Diode Recovery voltage slope	4.5	4.5	V/ns
V <sub>ISO</sub>	Insulation Withstand Voltage (DC)	_	- 2000	
T <sub>stg</sub>	Storage Temperature	-65 t	-65 to 150	
Tj	Max. Operating Junction Temperature	1	150	

#### **Table 4. Thermal Data**

Symbol	Parameter -		Va	Unit	
Syllibol			TO-220	TO220-FP	- Ollik
R <sub>thj-case</sub>	Thermal Resistance Junction-case	Max	1.56	3.57	°C/W
$R_{thj-amb}$	Thermal Resistance Junction-ambient	Max	6	62.5	°C/W
TI	Maximum Lead Temperature For Solde Purpose	ring	300		°C

## **Table 5. Avalanche Characteristics**

Symbol	Parameter	Max Value	Unit
I <sub>AR</sub>	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by $T_j$ max, $\delta$ < 1%)	3.3	А
Eas	Single Pulse Avalanche Energy (starting $T_j = 25$ °C; $I_D = I_{AR}$ ; $V_{DD} = 50$ V)	100	mJ

Note: 1. Pulse width limited by safe operating area 2.  $I_{SD} \le 7A$ ,  $di/dt \le 200 \ A/\mu s$ ,  $V_{DD} \le V(_{BR})_{DSS}$ ,  $T_j \le T_{JMAX}$ 

# **ELECTRICAL CHARACTERISTICS** (T<sub>case</sub> = 25°C unless otherwise specified)

#### Table 6. Off

Symbol	Parameter	Test Conditions		Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A \ V_{GS} = 0$	600			V
I <sub>DSS</sub>	Zero Gate Voltage	V <sub>DS</sub> = Max Rating			1	μΑ
	Drain Current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = Max Rating; Tc = 125 °C			50	μΑ
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	$V_{GS} = \pm 30 \text{ V}$			± 100	nA

# Table 7. On <sup>(1)</sup>

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}; I_D = 250 \mu A$	3	4	5	V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	V <sub>GS</sub> = 10V; I <sub>D</sub> = 1.6 A		3.3	3.6	Ω

Note: 1. Pulsed: Pulse duration = 300  $\mu\text{s},$  duty cycle 1.5 %

## **Table 8. Dynamic**

Symbol	Parameter	Test Conditions		Тур.	Max.	Unit
gfs (1)	Forward Transconductance	$V_{DS} > I_{D(on)} \times R_{DS(on)max}; I_D = 1.6 A$	1.2	2		S
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V f = 1 MHz V <sub>GS</sub> = 0		400	520	pF
Coss	Output Capacitance			57	77	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			7	9	pF

Note: 1. Pulsed: Pulse duration = 300  $\mu$ s, duty cycle 1.5 %

# Table 9. Switching On

Symbol	Parameter	Test Conditions M		Тур.	Max.	Unit
td(on)	Turn-on Time	$V_{DD} = 300 \text{ V}; I_D = 1.6 \text{ A}; R_G = 4.7 \Omega$		11	17	ns
tr	Rise Time	V <sub>GS</sub> = 10 V (see test circuit, Figure 18)		7	11	ns
Qg	Total Gate Charge	V <sub>DD</sub> = 480 V; I <sub>D</sub> = 3.3 A; V <sub>GS</sub> = 10 V		15	22	nC
$Q_{gs}$	Gate-Source Charge			6.2		nC
$Q_{gd}$	Gate-Drain Charge			5.6		nC

# Table 10. Switching Off

Symbol	Parameter	Test Conditions		Тур.	Max.	Unit
$t_{r(Voff)}$	Off-voltage Rise Time	$V_{DD} = 480 \text{ V}; I_D = 3.3 \text{ A}; R_G = 4.7 \Omega$		11	16	ns
t <sub>f</sub>	Fall Time	V <sub>GS</sub> = 10 V; (see test circuit, Figure 20)		13	18	ns
t <sub>c</sub>	Cross-over Time			18	25	ns

**Table 11. Source Drain Diode** 

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain Current				3.3	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain Current (pulsed)				13.2	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward On Voltage	I <sub>SD</sub> = 3.3 A V <sub>GS</sub> = 0			1.6	V
t <sub>rr</sub>	Reverse Recovery Time	$I_{SD} = 3.3 \text{ A}$ ; di/dt = 100 A/ $\mu$ s		500		ns
Q <sub>rr</sub>	Reverse RecoveryCharge	$V_{DD}$ = 100 V; $T_j$ = 150 °C (see test circuit, Figure 20)		2.1		μС
I <sub>RRAM</sub>	Reverse RecoveryCharge			8.5		Α

Note: 1. Pulse width limited by safe operating area

2. Pulsed: Pulse duration = 300  $\mu$ s, duty cycle 1.5 %

Figure 3. Safe Operating Area for TO-220

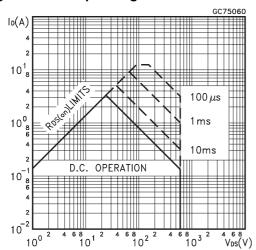


Figure 5. Thermal Impedance for TO-220

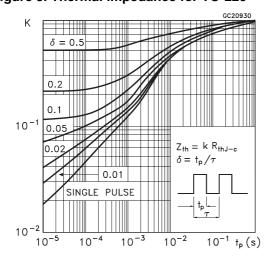


Figure 4. Safe Operating Area for TO-220FP

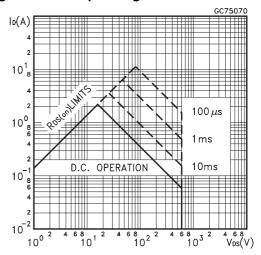


Figure 6. Thermal Impedance for TO-220FP

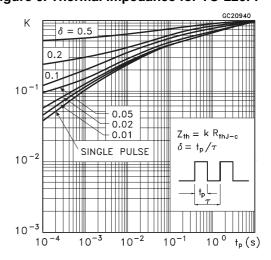


Figure 7. Output Characteristics

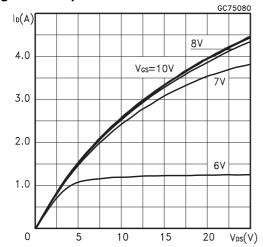


Figure 8. Transfer Characteristics

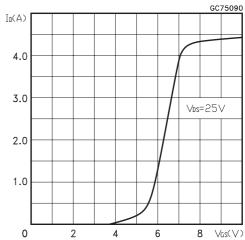


Figure 9. Transconductance

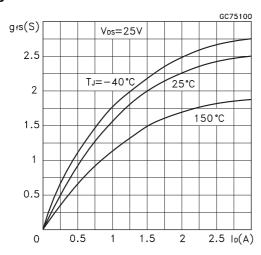


Figure 10. Static Drain-source On Resistance

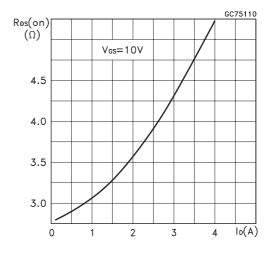


Figure 11. Gate Charge vs Gate-source Voltage

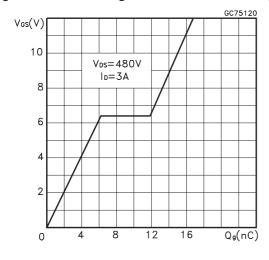
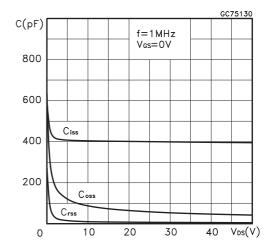


Figure 12. Capacitance Variations



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Figure 13. Normalized Gate Thresold Voltage vs Temperature

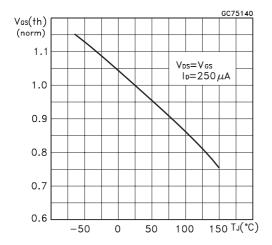


Figure 14. Normalized On Resistance vs Temperature

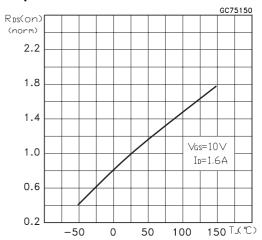


Figure 15. Source-drain Diode Forward Characteristics

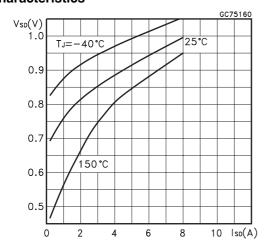


Figure 16. Unclamped Inductive Load Test Circuit

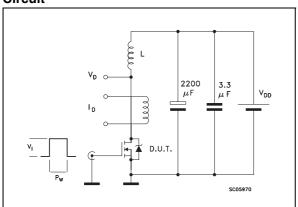


Figure 17. Unclamped Inductive Waveforms

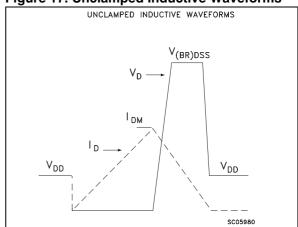


Figure 18. Switching Times Test Circuits For **Resistive Load** 

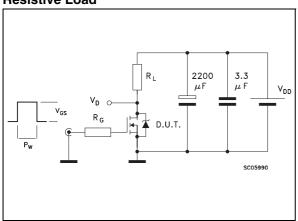


Figure 19. Gate Charge Test Circuit

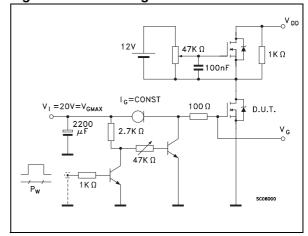
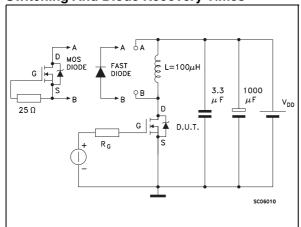


Figure 20. Test Circuit For Inductive Load **Switching And Diode Recovery Times** 

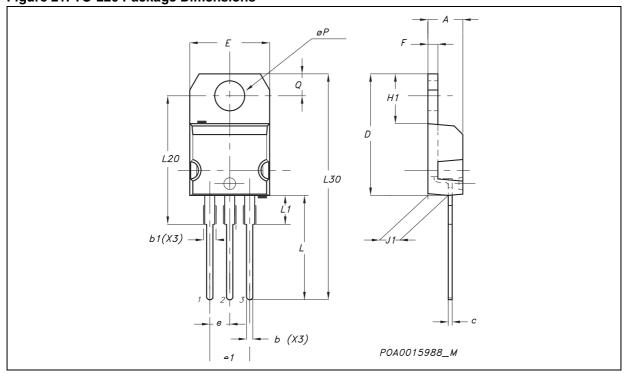


# **PACKAGE MECHANICAL**

Table 12. TO-220 Mechanical Data

Compleal		millimeters			inches	
Symbol	Min	Тур	Max	Min	Тур	Max
Α	4.40		4.60	0.173		0.181
b	0.61		0.88	0.024		0.034
b1	1.15		1.70	0.045		0.066
С	0.49		0.70	0.019		0.027
D	15.25		15.75	0.60		0.620
E	10		10.40	0.393		0.409
е	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
F	1.23		1.32	0.048		0.052
H1	6.20		6.60	0.244		0.256
J1	2.40		2.72	0.094		0.107
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L20		16.40			0.645	
L30		28.90			1.137	
ØP	3.75		3.85	0.147		0.151
Q	2.65		2.95	0.104		0.116

Figure 21. TO-220 Package Dimensions

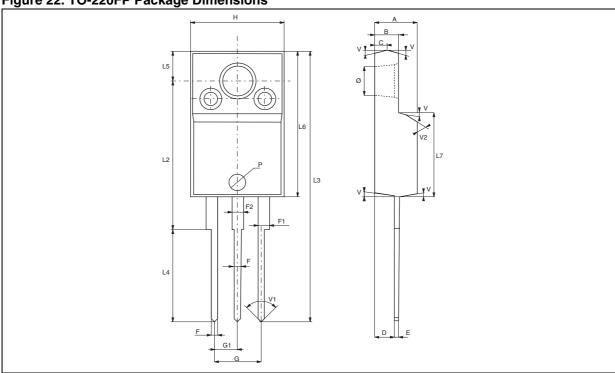


Note: Drawing is not to scale.

Table 13. TO-220FP Mechanical Data

Symbol	millimeters			inches		
	Min	Тур	Max	Min	Тур	Max
Α	4.40		4.60	0.173		0.181
В	2.50		2.70	0.098		0.106
С	1.00		1.30	0.039		0.051
D	2.50		2.75	0.098		0.108
Е	0.40		0.70	0.016		0.027
F	0.75		1.00	0.030		0.039
F1	1.15		1.70	0.045		0.066
F2	1.15		1.70	0.045		0.066
G	4.95		5.20	0.195		0.204
G1	2.40		2.70	0.094		0.106
Н	10.00		10.40	0.393		0.409
L2		16.00			0.630	
L3	28.60		30.60	1.126		1.204
L4	9.80		10.60	0.385		0.417
L5	3.30		3.50	0.129		0.137
L6	15.90		16.40	0.626		0.645
L7	9.00		9.30	0.354		0.366
Р			1.60			0.063
V		5°			5°	
V1	50°		100°	50°		100°
V2	44°		46°	44°		46°
Ø	3.00		3.20	0.118		0.126

Figure 22. TO-220FP Package Dimensions



Note: Drawing is not to scale.

# STP3NB60/FP

## **REVISION HISTORY**

**Table 14. Revision History** 

Date	Revision	Description of Changes
March-1998	1	First Issue
14-Apr-2004	2	Stylesheet update. No content change.

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